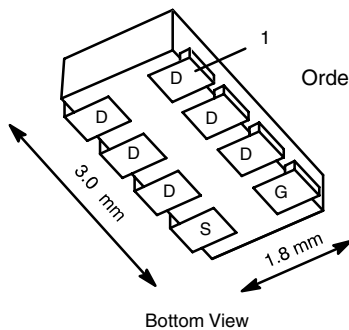


P-Channel 12-V (D-S) MOSFET

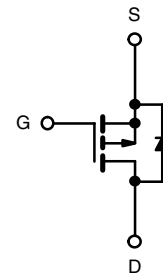
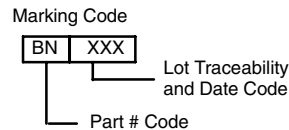
PRODUCT SUMMARY			
V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A) ^a	Q_g (Typ)
- 12	0.028 at $V_{GS} = - 4.5$ V	- 6	15.5 nC
	0.039 at $V_{GS} = - 2.5$ V	- 6	
	0.054 at $V_{GS} = - 1.8$ V	- 6	

FEATURES

- TrenchFET[®] Power MOSFET: 1.8-V Rated

RoHS
COMPLIANT1206-8 ChipFET[®]

Ordering Information: Si5475BDC-T1—E3 (Lead (Pb)—free)



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A = 25$ °C, unless otherwise noted				
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	- 12	V	
Gate-Source Voltage	V_{GS}	± 8		
Continuous Drain Current ($T_J = 150$ °C)	I_D	$T_C = 25$ °C	- 6 ^a	A
		$T_C = 70$ °C	- 6 ^a	
		$T_A = 25$ °C	- 7.7 ^{b,c}	
		$T_A = 70$ °C	- 6.2 ^{b,c}	
Pulsed Drain Current	I_{DM}	- 20		
Continuous Source-Drain Diode Current	I_S	$T_C = 25$ °C	- 5.2	
		$T_A = 25$ °C	- 1.3 ^{b,c}	
Maximum Power Dissipation	P_D	$T_C = 25$ °C	6.3	W
		$T_C = 70$ °C	4	
		$T_A = 25$ °C	2.5 ^{b,c}	
		$T_A = 70$ °C	1.6 ^{b,c}	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature) ^{d,e}		260		

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, f}	R_{thJA}	40	50	°C/W	
Maximum Junction-to-Foot (Drain)	R_{thJF}	15	20		

Notes:

- Package Limited.
- Surface mounted on 1" x 1" FR4 board.
- $t = 5$ sec.
- See Solder Profile (<http://www.vishay.com/doc?73257>). The 1206 ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- Maximum under steady state conditions is 95 °C/W.

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$	- 12			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250\text{ }\mu\text{A}$		- 7		mV/ $^\circ\text{C}$
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		2.5			
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$	- 0.45		- 1.0	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0\text{ V}, V_{GS} = \pm 8\text{ V}$			± 100	ns
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -12\text{ V}, V_{GS} = 0\text{ V}$			- 1	μA
		$V_{DS} = -12\text{ V}, V_{GS} = 0\text{ V}, T_J = 55\text{ }^\circ\text{C}$			- 10	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \leq 5\text{ V}, V_{GS} = -4.5\text{ V}$	- 20			A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = -4.5\text{ V}, I_D = -5.6\text{ A}$		0.023	0.028	Ω
		$V_{GS} = -2.5\text{ V}, I_D = -4.7\text{ A}$		0.032	0.039	
		$V_{GS} = -1.8\text{ V}, I_D = -1.9\text{ A}$		0.044	0.054	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -6\text{ V}, I_D = -6.9\text{ A}$		22		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = -6\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$		1400		pF
Output Capacitance	C_{oss}		370			
Reverse Transfer Capacitance	C_{rss}		260			
Total Gate Charge	Q_g	$V_{DS} = -6\text{ V}, V_{GS} = -8\text{ V}, I_D = -6\text{ A}$		26	40	nC
				15.5	24	
Gate-Source Charge	Q_{gs}	$V_{DS} = -6\text{ V}, V_{GS} = -4.5\text{ V}, I_D = -6\text{ A}$		2.1		
Gate-Drain Charge	Q_{gd}		4.0			
Gate Resistance	R_g	$f = 1\text{ MHz}$		9		Ω
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -6\text{ V}, R_L = 0.97\text{ }\Omega$ $I_D \cong -6.2\text{ A}, V_{GEN} = -4.5\text{ V}, R_g = 1\text{ }\Omega$		10	15	ns
Rise Time	t_r		38	60		
Turn-Off Delay Time	$t_{d(off)}$		62	95		
Fall Time	t_f		70	105		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -6\text{ V}, R_L = 0.97\text{ }\Omega$ $I_D \cong -6.2\text{ A}, V_{GEN} = -8\text{ V}, R_g = 1\text{ }\Omega$		5	10	
Rise Time	t_r		15	25		
Turn-Off Delay Time	$t_{d(off)}$		65	100		
Fall Time	t_f		72	110		
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^\circ\text{C}$			- 5.2	A
Pulse Diode Forward Current	I_{SM}				- 20	
Body Diode Voltage	V_{SD}	$I_S = -6.2\text{ A}, V_{GS} = 0\text{ V}$		- 0.9	- 1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = -6.2\text{ A}, di/dt = 100\text{ A}/\mu\text{s}, T_J = 25\text{ }^\circ\text{C}$		45	70	ns
Body Diode Reverse Recovery Charge	Q_{rr}		27	42	nC	
Reverse Recovery Fall Time	t_a		15		ns	
Reverse Recovery Rise Time	t_b		30			

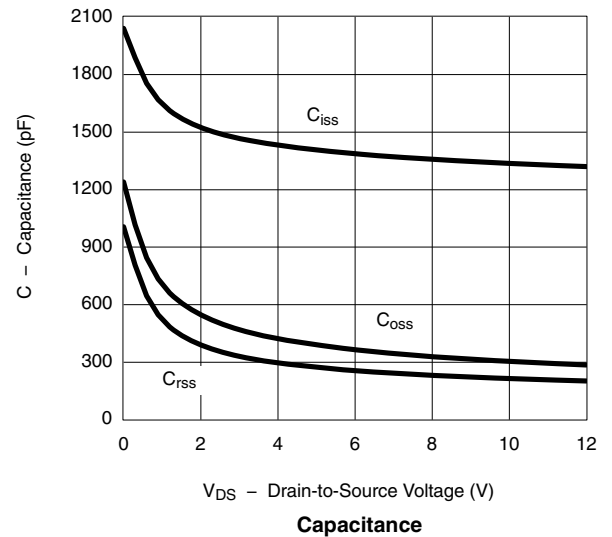
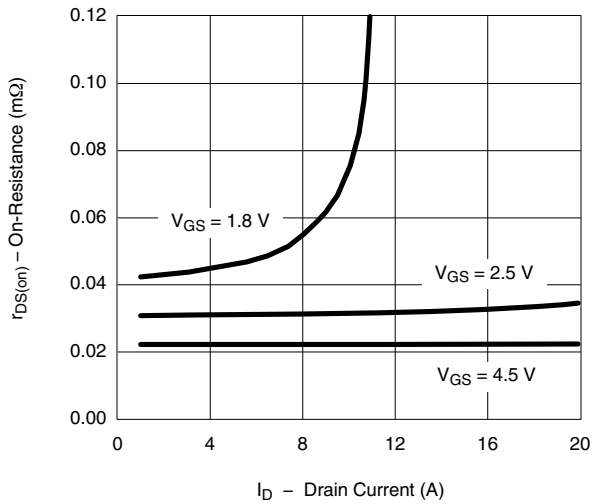
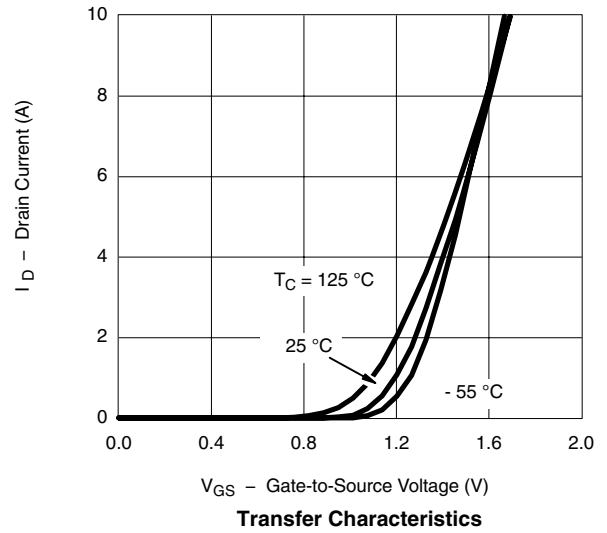
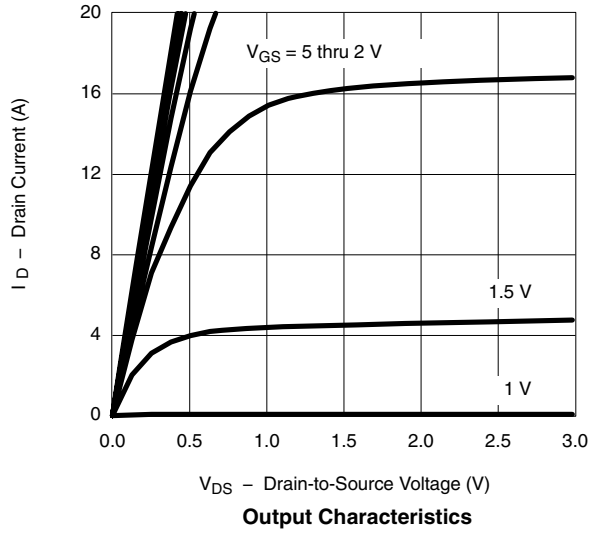
Notes:

- a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

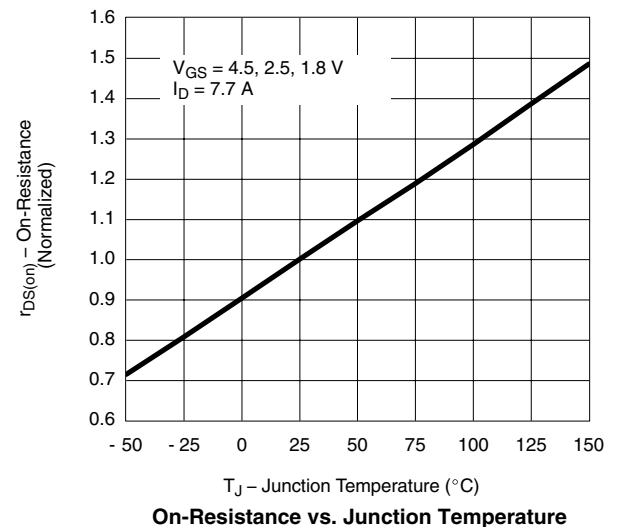
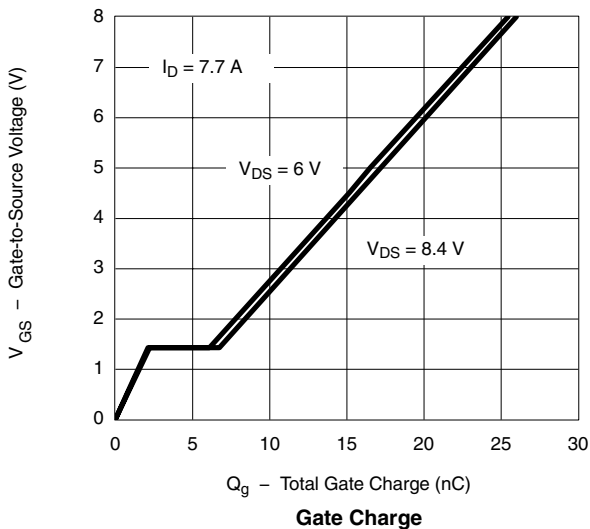


TYPICAL CHARACTERISTICS 25 °C unless noted



On-Resistance vs. Drain Current and Gate Voltage

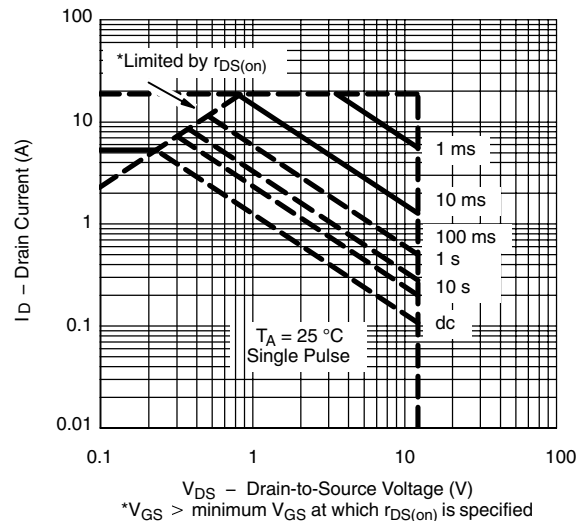
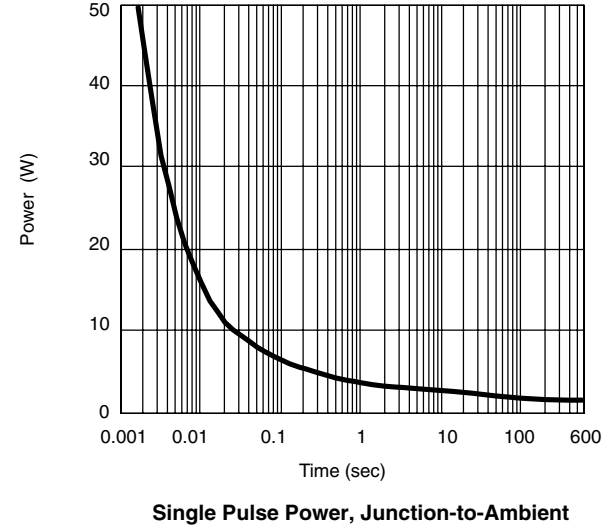
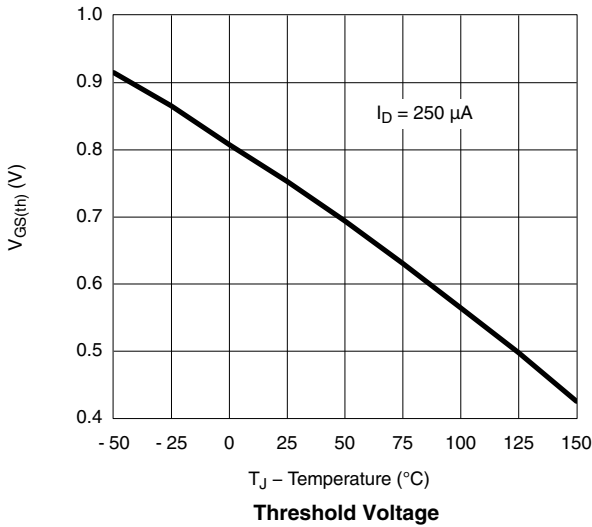
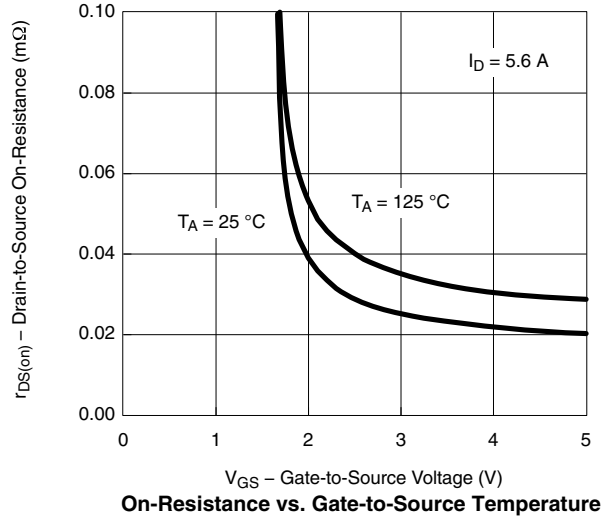
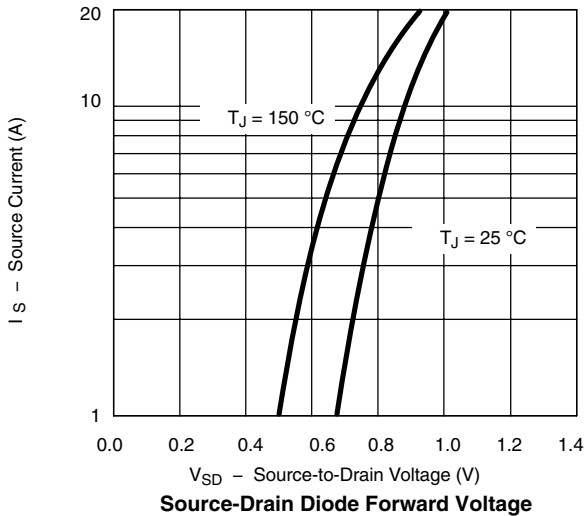
Capacitance



On-Resistance vs. Junction Temperature

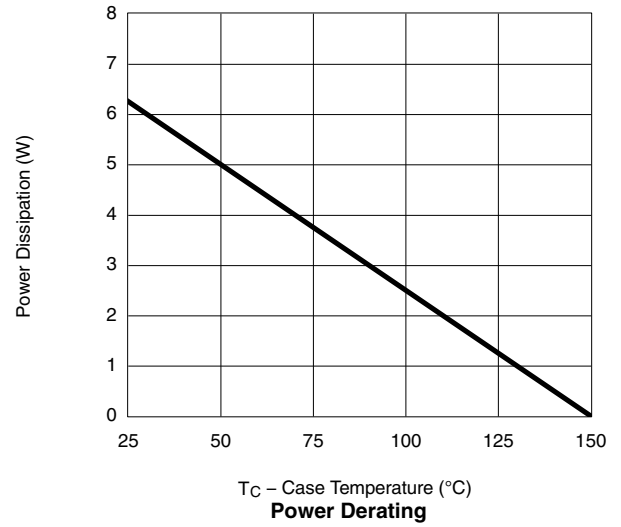
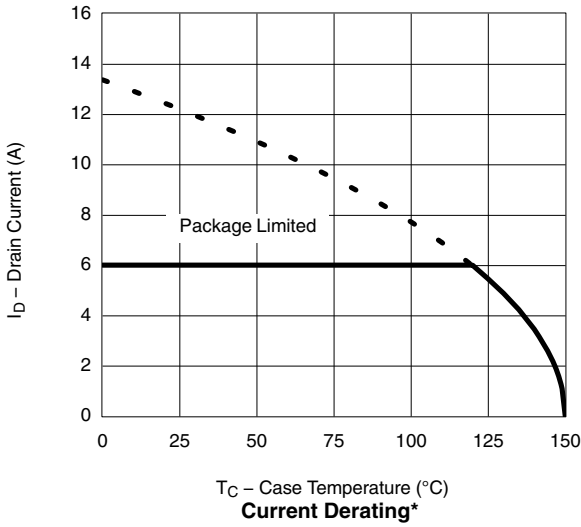


TYPICAL CHARACTERISTICS 25 °C unless noted





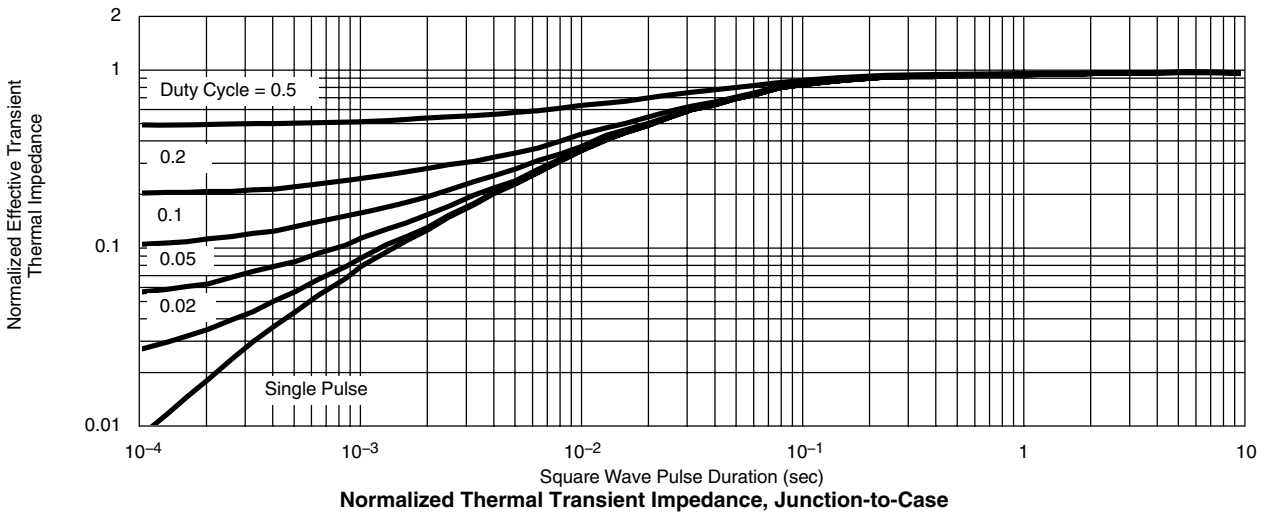
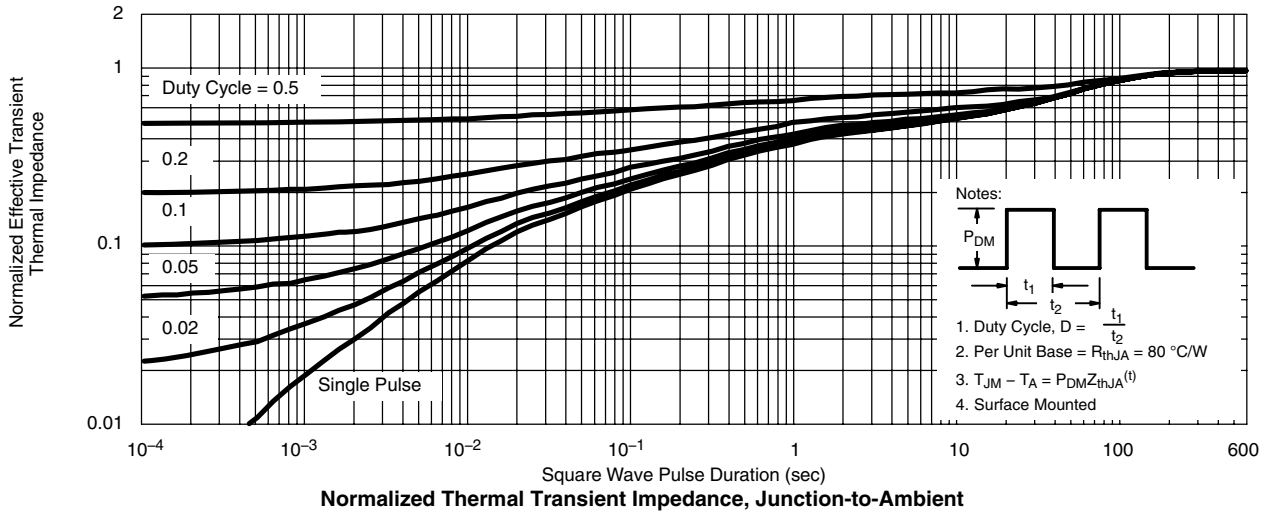
TYPICAL CHARACTERISTICS 25 °C unless noted



* The power dissipation PD is based on $T_{J(max)} = 150\text{ °C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 °C unless noted



Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see <http://www.vishay.com/ppg?73381>.



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